November 2018

FQB8P10 — P-Channel QFET[®] MOSFET

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P-Channel QFET[®] MOSFET

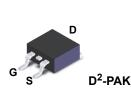
-100 V, -8.0 A, 530 mΩ

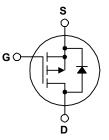
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- -8.0 A, -100 V, $\mathsf{R}_{\mathsf{DS}(\mathsf{on})}$ = 530 m Ω (Max.) @ V_{GS} = -10 V, I_D = -4.0 A
- Low Gate Charge (Typ. 12 nC)
- Low Crss (Typ. 30 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating





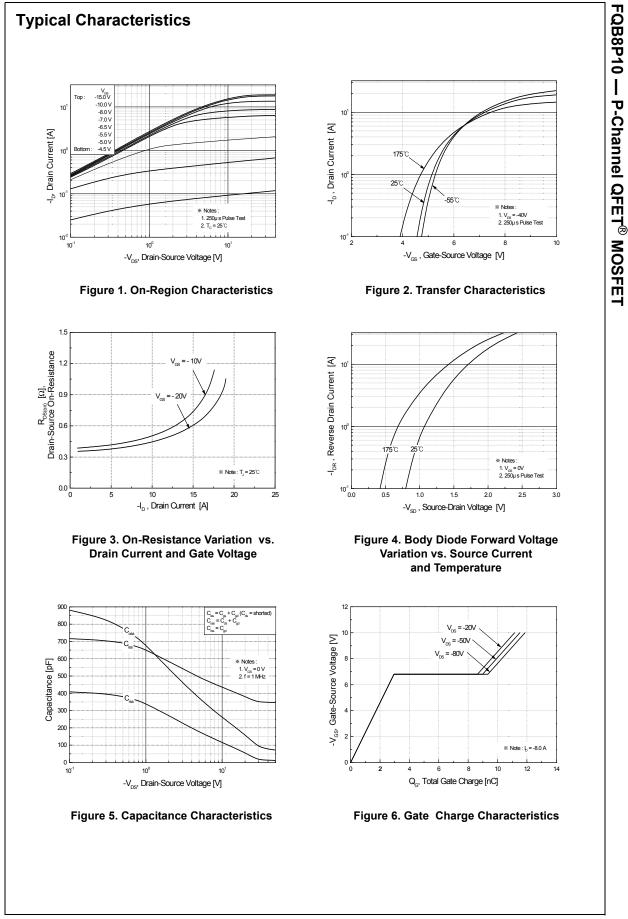
Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

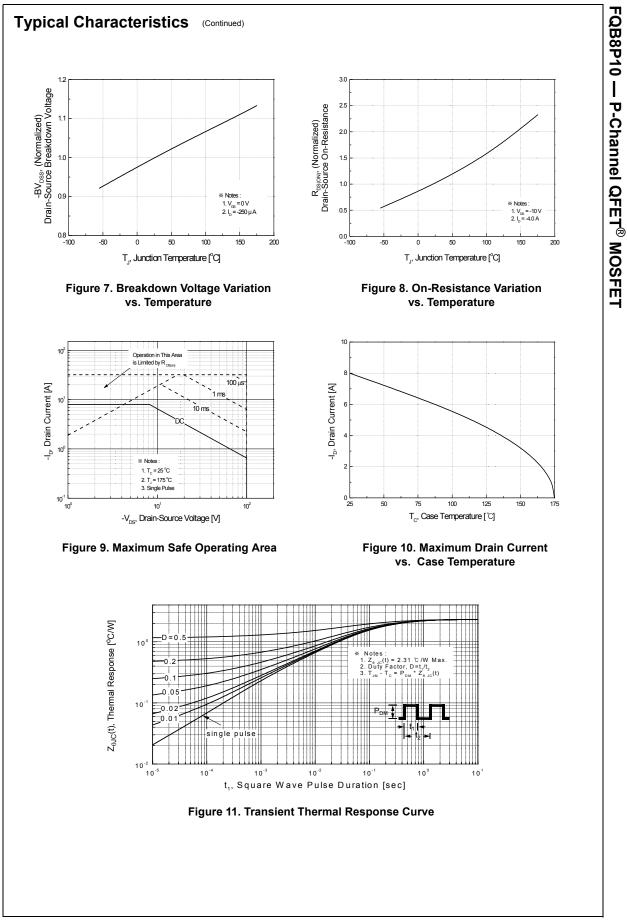
Symbol	Parameter		FQB8P10TM	Unit
V _{DSS}	Drain-Source Voltage		-100	V
I _D	Drain Current - Continuous ($T_C = 25^{\circ}C$)		-8.0	А
	- Continuous (T _C = 100°C)		-5.7	А
I _{DM}	Drain Current - Pulsed	(Note 1)	-32	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	150	mJ
I _{AR}	Avalanche Current	(Note 1)	-8.0	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	6.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-6.0	V/ns
P _D	Power Dissipation $(T_A = 25^{\circ}C)^{*}$		3.75	W
	Power Dissipation $(T_C = 25^{\circ}C)$		65	W
	- Derate above 25°C		0.43	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
TL	Maximum lead temperature for soldering, 1/8" from case for 5 seconds.		300	°C

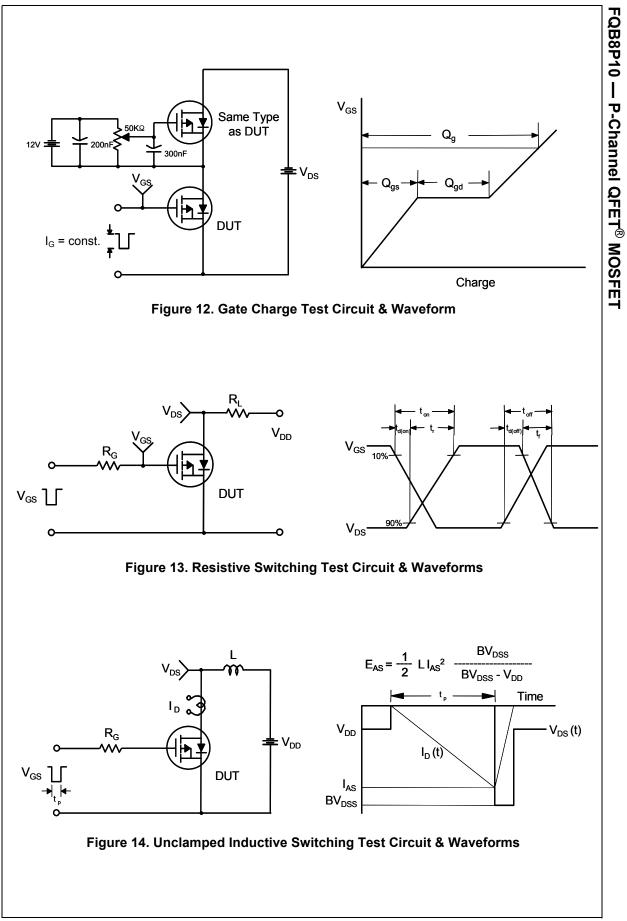
Thermal Characteristics

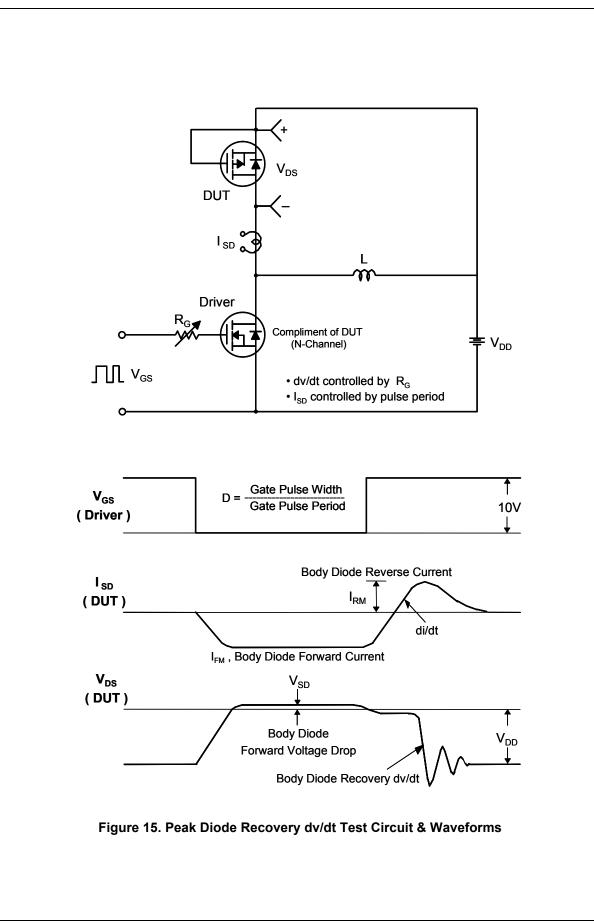
Symbol	Parameter	FQB8P10TM	Unit
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	2.31	
R_{\thetaJA}	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	62.5	°C/W
	Thermal Resistance, Junction to Ambient (*1 in ² Pad of 2-oz Copper), Max.	40	

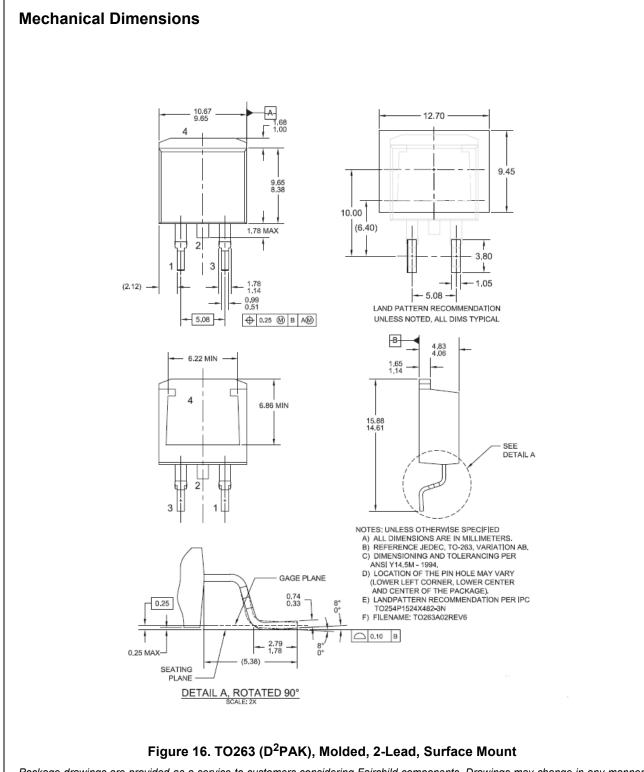
SymbolParameterTest ConditionsOff Characteristics BV_{DSS} Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = -250 \mu \text{ A}$ ΔBV_{DSS} Breakdown Voltage Temperature Coefficient $I_D = -250 \mu \text{ A}$, Referenced to 25°C ΔSV Zero Gate Voltage Drain Current $V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$ V_{DS} Gate-Body Leakage Current, Forward $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ $GSSF$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ $GSSR$ Gate Threshold Voltage $V_{DS} = -250 \mu \text{ A}$ $V_{GS}(th)$ Gate Threshold Voltage $V_{DS} = -10 \text{ V}, I_D = -250 \mu \text{ A}$ $V_{GS}(th)$ Gate Threshold Voltage $V_{DS} = -10 \text{ V}, I_D = -250 \mu \text{ A}$ $On-Resistance$ $V_{GS} = -10 \text{ V}, I_D = -4.0 \text{ A}$ $On-Resistance$ $V_{DS} = -40 \text{ V}, I_D = -4.0 \text{ A}$ $On-Resistance$ $V_{DS} = -40 \text{ V}, I_D = -4.0 \text{ A}$ $On-Resistance$ $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ $On-Resistance$ $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ $On-Resistance$ $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ $On-Resistance$ $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ O_{Tras} Input Capacitance $V_{DS} = -25 \text{ V}, V_{DS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ C_{rss} Input Capacitance $V_{DS} = -25 \text{ V}, V_{CS} = 0 \text{ V}, I_D = -3.0 \text{ A}, R_G = 25 \Omega$ C_{rss} Reverse Transfer Capacitance $V_{DS} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ G_{rss} Tu			/idth	Quantity 800 units	
SymbolParameterTest ConditionsOff Characteristics BV_{DSS} Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, \text{ I}_D = -250 \ \mu\text{A}$ ΔBV_{DSS} Breakdown Voltage Temperature Coefficient $\text{I}_D = -250 \ \mu\text{A}$, Referenced to 25°C $/\Delta T_J$ Coefficient $V_{DS} = -100 \ V, V_{GS} = 0 \ V$ DSS Zero Gate Voltage Drain Current $V_{DS} = -30 \ V, \ V_{DS} = 0 \ V$ N_{DS} Gate-Body Leakage Current, Forward $V_{GS} = -30 \ V, \ V_{DS} = 0 \ V$ N_{GSR} Gate Body Leakage Current, Reverse $V_{GS} = 30 \ V, \ V_{DS} = 0 \ V$ On Characteristics $V_{GS} = -10 \ V, \ I_D = -250 \ \mu A$ $N_{SS(th)}$ Gate Threshold Voltage $V_{DS} = V_{GS}, \ I_D = -250 \ \mu A$ $N_{SS(th)}$ Gate Threshold Voltage $V_{DS} = -30 \ V, \ V_{DS} = 0 \ V$ $On-Resistance$ $V_{GS} = -10 \ V, \ I_D = -4.0 \ A$ $Dynamic Characteristics$ $V_{DS} = -40 \ V, \ I_D = -4.0 \ A$ C_{SS} Input Capacitance $V_{DS} = -25 \ V, \ V_{GS} = 0 \ V, \ f = 1.0 \ MHz$ C_{SS} Input Capacitance $V_{DS} = -25 \ V, \ V_{GS} = 0 \ V, \ f = 1.0 \ MHz$ C_{SS} Num-Off Delay Time $V_{DD} = -50 \ V, \ I_D = -8.0 \ A, \ R_G = 25 \ \Omega$ N_{GS} Total Gate Charge $V_{DS} = -80 \ V, \ I_D = -8.0 \ A, \ R_G = 25 \ \Omega$ N_{GS} Gate-Drain Charge $V_{DS} = -10 \ V$ N_{G	mm	24 m	m		
Off Characteristics BV _{DSS} Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, \text{ I}_{D} = -250 \mu \text{A}$ ABV _{DSS} Breakdown Voltage Temperature Coefficient $I_D = -250 \mu \text{A}$, Referenced to 25°C DSS Zero Gate Voltage Drain Current $V_{DS} = -100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ DSS Zero Gate Voltage Drain Current $V_{DS} = -30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$ GSSR Gate-Body Leakage Current, Forward $V_{GS} = -30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$ On Characteristics V_{GS} = 30 \text{ V}, \text{ V}_{DS} = 0 \text{ V} On Characteristics V_{GS} = -10 \text{ V}, \text{ I}_{D} = -250 \mu \text{A} VGS(th) Gate Threshold Voltage $V_{DS} = -30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$ On Characteristics V_{GS} = -10 \text{ V}, \text{ I}_{D} = -4.0 \text{ A} On-Resistance $V_{DS} = -40 \text{ V}, \text{ I}_{D} = -4.0 \text{ A}$ Dynamic Characteristics V_{DS} = -25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ I}_{D} = -4.0 \text{ A} Cess Input Capacitance $V_{DS} = -25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ I}_{D} = -4.0 \text{ A}$ Cess Output Capacitance $V_{DS} = -25 \text{ V}, \text{ I}_{D} = -8.0 \text{ A}, \text{ R}_{G} = 25 \Omega$ Cess Nutput Capacitance $V_{DS} = -50 \text{ V}, \text{ I}_{D} = -8.0 \text{ A}, \text{ R}_{G} = 25 \Omega$ Cidoft) Turn-On Rise Time					
BVDSS BVDSS ABVDSSDrain-Source Breakdown Voltage Toru-Source Breakdown Voltage Temperature 	Min.	Тур.	Max.	. Unit	
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DSSZero Gate Voltage Drain Current $V_{DS} = -100 \text{ V}, V_{GS} = 0 \text{ V}$ GSSFGate-Body Leakage Current, Forward $V_{GS} = -80 \text{ V}, V_{DS} = 0 \text{ V}$ GSSRGate-Body Leakage Current, Reverse $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ On Characteristics $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ (SS(th)Gate Threshold Voltage $V_{DS} = -250 \mu \text{A}$ (SG(th)Gate Threshold Voltage $V_{GS} = -10 \text{ V}, I_D = -250 \mu \text{A}$ (SG(th)Gate Threshold Voltage $V_{GS} = -10 \text{ V}, I_D = -4.0 \text{ A}$ (Prs)Forward Transconductance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ (Siss)Input Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ (Coss)Output Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ (Coss)Output Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ (Coss)Output Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ (Coss)Output Capacitance $V_{DD} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ (doff)Turn-On Rise Time $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ (Note 4) V_{QS} Gate-Drain Charge(Note 4) V_{QS} $V_{QS} = -10 \text{ V}$ (Note 4) V_{QS} $V_{OS} = -10 \text{ V}$ (Note 4) V_{QS} $V_{OS} = -10 \text{ V}$ (Note 4) V_{QS} $V_{OS} = -10 \text{ V}$ (Note 4) V_{QS} $V_{QS} = -10 \text{ V}$ (Note 4) V_{QS} $V_{OS} = -10 \text{ V}$ (Note 4) $V_$		-0.1		V/°C	
Zero Gate Voltage Drain Current $V_{DS} = -80 \text{ V}, T_C = 150^{\circ}\text{C}$ GSSFGate-Body Leakage Current, Forward $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ GSSRGate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ On Characteristics $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ On Characteristics $V_{GS} = -10 \text{ V}, I_D = -250 \mu \text{ A}$ $\langle R_{DS}(on)$ Static Drain-Source On-Resistance $V_{GS} = -10 \text{ V}, I_D = -4.0 \text{ A}$ O_{FS} Forward Transconductance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ Opnamic Characteristics $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ O_{TSS} Input Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ O_{Coss} Output Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ O_{Coss} Output Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ O_{Coss} Output Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ O_{Coss} Output Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = -4.0 \text{ A}$ O_{Coss} Output Capacitance $V_{DS} = -25 \text{ V}, V_{DS} = 0 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ (aon) Turn-On Rise Time $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, V_{GS} = -10 \text{ V}$ r Turn-Off Fall Time $V_{DS} = -10 \text{ V}$ A_{gg} Gate-Drain Charge $V_{DS} = -10 \text{ V}$ A_{gg} Gate-Drain Charge $V_{OS} = -10 \text{ V}$ A_{gg} Gate-Drain Charge(Note 4) O_{gg} Maximum Contin			-1		
GSSFGate-Body Leakage Current, Forward $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$ GSSRGate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ On Characteristics $V_{GS}(h)$ Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = -250 \mu \text{A}$ $N_{GS}(n)$ Static Drain-Source On-Resistance $V_{GS} = -10 \text{ V}, I_D = -4.0 \text{ A}$ Opmamic Characteristics $V_{DS} = -40 \text{ V}, I_D = -4.0 \text{ A}$ Opmamic Characteristics $V_{DS} = -40 \text{ V}, I_D = -4.0 \text{ A}$ Opmamic Characteristics $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ ClassInput Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ ClassOutput Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ ClassOutput Capacitance $V_{DD} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ Witching Characteristics $V_{DD} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ Gate Turn-Off Fall Time $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ A_{Gg} Total Gate Charge $V_{DS} = -10 \text{ V}$ A_{Gg} Gate-Drain Charge $V_{DS} = -10 \text{ V}$ Orain-Source Diode Characteristics and Maximum RatingssMaximum Continuous Drain-Source Diode Forward CurrentssMaximum Pulsed Drain-Source Diode Forward Current			-10	μΑ μΑ	
Gass GassGate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$ On CharacteristicsV VGSV VDSV 			-100	nA	
On Characteristics $V_{GS(th)}$ Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$ $R_{DS(on)}$ Static Drain-Source On-Resistance $V_{GS} = -10 \ V$, $I_D = -4.0 \ A$ O_{FS} Forward Transconductance $V_{DS} = -40 \ V$, $I_D = -4.0 \ A$ Dynamic Characteristics C_{iss} Input Capacitance $V_{DS} = -25 \ V$, $V_{GS} = 0 \ V$, f = 1.0 MHz C_{oss} Output Capacitance $V_{DS} = -25 \ V$, $V_{GS} = 0 \ V$, f = 1.0 MHzSwitching Characteristics $V_{DD} = -50 \ V$, $I_D = -8.0 \ A$, $R_G = 25 \ \Omega$ C_{inf} Turn-On Delay Time f f $V_{DS} = -50 \ V$, $I_D = -8.0 \ A$, $R_G = 25 \ \Omega$ A_{Qg} Gate-Drain Charge $V_{DS} = -80 \ V$, $I_D = -8.0 \ A$, $V_{GS} = -10 \ V$ A_{Qg} Gate-Drain Charge $V_{DS} = -80 \ V$, $I_D = -8.0 \ A$, $V_{GS} = -10 \ V$ Drain-Source Diode Characteristics and Maximum Ratings SMaximum Continuous Drain-Source Diode Forward CurrentSMaximum Pulsed Drain-Source Diode Forward Current			100	nA	
$V_{GS(th)}$ Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$ $R_{DS(on)}$ Static Drain-Source On-Resistance $V_{GS} = -10 \ V$, $I_D = -4.0 \ A$ O_{FS} Forward Transconductance $V_{DS} = -40 \ V$, $I_D = -4.0 \ A$ Oynamic Characteristics $V_{DS} = -40 \ V$, $I_D = -4.0 \ A$ Oynamic Characteristics $V_{DS} = -40 \ V$, $I_D = -4.0 \ A$ Oynamic Characteristics $V_{DS} = -40 \ V$, $I_D = -4.0 \ A$ Oynamic Characteristics $V_{DS} = -25 \ V$, $V_{GS} = 0 \ V$, $f = 1.0 \ MHz$ C_{OSS} Output Capacitance Output Capacitance $V_{DS} = -25 \ V$, $V_{GS} = 0 \ V$, $f = 1.0 \ MHz$ C_{OSS} Output Capacitance Output Capacitance $V_{DS} = -25 \ V$, $V_{GS} = 0 \ V$, $f = 1.0 \ MHz$ C_{OSS} Output Capacitance Output Capacitance $V_{DS} = -25 \ V$, $V_{GS} = 0 \ V$, $f = 1.0 \ MHz$ C_{OSS} Output Capacitance Turn-On Delay Time r Turn-On Rise Time f $V_{DD} = -50 \ V$, $I_D = -8.0 \ A$, $R_G = 25 \ \Omega$ A_{Gg} Total Gate Charge Q_{gg} $V_{DS} = -80 \ V$, $I_D = -8.0 \ A$, $V_{GS} = -10 \ V$ A_{gg} Gate-Drain Charge $V_{DS} = -10 \ V$ $O_{Gate-Drain Charge}$ $(Note 4)$ $V_{GS} = -10 \ V$ $(Note 4)$ $O_{FS} = -10 \ V$ $(Note 4)$ $O_{FS} = Maximum Continuous Drain-Source Diode Forward CurrentSM$					
$R_{DS(on)}$ Static Drain-Source On-Resistance $V_{GS} = -10 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ Q_{FS} Forward Transconductance $V_{DS} = -40 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ Oynamic Characteristics $V_{DS} = -40 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ Oynamic Characteristics $V_{DS} = -40 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ Oynamic Characteristics $V_{DS} = -40 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ C _{iss} Input Capacitance $V_{DS} = -40 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ C _{iss} Input Capacitance $V_{DS} = -40 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ C _{iss} Input Capacitance $V_{DS} = -40 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ C _{iss} Input Capacitance $V_{DS} = -25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ C _{iss} Output Capacitance $V_{DS} = -25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ C _{iss} Output Capacitance $V_{DS} = -25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ C _{iss} Reverse Transfer Capacitance $V_{DS} = -25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ I}_D = -4.0 \text{ A}$ ST urn-On Delay Time f $V_{DD} = -50 \text{ V}, \text{ I}_D = -8.0 \text{ A}, \text{ R}_G = 25 \Omega$ A_{ig} Total Gate Charge A_{gg} $V_{DS} = -80 \text{ V}, \text{ I}_D = -8.0 \text{ A}, \text{ V}_{GS} = -10 \text{ V}$ A_{gg} Gate-Drain Charge $(Note 4)$ Drain-Source Diode Characteristics and Maximum Ratings sMaximum Continuous Drain-Source Diode Forward CurrentsmMaximum Pulsed Drain-Source Diode Forward Current	-2.0		-4.0	V	
Dynamic Characteristics C_{iss} Input Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ C_{oss} Output Capacitance $f = 1.0 \text{ MHz}$ C_{rss} Reverse Transfer Capacitance $V_{DD} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ Switching Characteristics $V_{DD} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ $d(off)$ Turn-Off Delay Time $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ f Turn-Off Fall Time $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, N_G = -10 \text{ V}$ Q_g Total Gate Charge $V_{GS} = -10 \text{ V}$ Q_{gd} Gate-Drain Charge $(Note 4)$ Drain-Source Diode Characteristics and Maximum RatingssMaximum Continuous Drain-Source Diode Forward CurrentsmMaximum Pulsed Drain-Source Diode Forward Current		0.41	0.53	Ω	
DissInput Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$ CossOutput Capacitance $f = 1.0 \text{ MHz}$ CrssReverse Transfer Capacitance $V_{DD} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ Switching Characteristics $V_{DD} = -50 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ $d(on)$ Turn-On Rise Time $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, R_G = 25 \Omega$ $d(off)$ Turn-Off Delay Time $(Note 4)$ f Turn-Off Fall Time $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, V_{GS} = -10 \text{ V}$ A_{gg} Gate-Source Charge $V_{GS} = -10 \text{ V}$ A_{gd} Gate-Drain Charge $(Note 4)$ Drain-Source Diode Characteristics and Maximum RatingssMaximum Continuous Drain-Source Diode Forward CurrentSMMaximum Pulsed Drain-Source Diode Forward Current		4.3		S	
Switching Characteristics $d(on)$ Turn-On Delay TimerTurn-On Rise Time $d(off)$ Turn-Off Delay TimefTurn-Off Fall Time Q_g Total Gate Charge Q_{gs} Gate-Source Charge Q_{gd} Gate-Drain Charge V_{GS} = -10 VOrain-Source Diode Characteristics and Maximum RatingssMaximum Continuous Drain-Source Diode Forward CurrentSMMaximum Pulsed Drain-Source Diode Forward Current		360 120 30	470 155 40	pF pF	
I_{urn} -On Delay Time V_{DD} = -50 V, I_D = -8.0 A, r_{urn} -On Rise Time V_{DD} = -50 V, I_D = -8.0 A, $I_{d(off)}$ Turn-Off Delay Time f_{f} Turn-Off Fall Time Q_g Total Gate Charge Q_{gs} Gate-Source Charge Q_{gd} Gate-Drain Charge Q_{gd} Gate-Drain Charge $Orain-Source Diode Characteristics and Maximum Ratingss_sMaximum Continuous Drain-Source Diode Forward CurrentSMMaximum Pulsed Drain-Source Diode Forward Current$				P.	
Turn-On Rise Time $v_{DD} = -30 \text{ V}, \text{ I}_D = -8.0 \text{ A}, \text{ R}_G = 25 \Omega$ $d(off)$ Turn-Off Delay Time $R_G = 25 \Omega$ f Turn-Off Fall Time $V_{DS} = -80 \text{ V}, \text{ I}_D = -8.0 \text{ A}, \text{ V}_{GS} = -10 \text{ V}$ Q_{gd} Gate-Drain Charge $V_{GS} = -10 \text{ V}$ Q_{gd} Gate-Drain Charge $(Note 4)$ Drain-Source Diode Characteristics and Maximum Ratings S S Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current		11	30	ns	
Image: dot off background (off) Turn-Off Delay Time Image: dot of the state (Note 4) f Turn-Off Fall Time (Note 4) A_g Total Gate Charge $V_{DS} = -80 \text{ V}, I_D = -8.0 \text{ A}, V_{GS} = -10 \text{ V}$ A_{gd} Gate-Drain Charge (Note 4) Drain-Source Diode Characteristics and Maximum Ratings s Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current		110	230	ns	
Autor Turn-Off Fall Time (Note 4) Ag Total Gate Charge VDS = -80 V, ID = -8.0 A, VGS = -10 V Agd Gate-Drain Charge (Note 4) Drain-Source Diode Characteristics and Maximum Ratings (Note 4) S Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current		20	50	ns	
Q_g Total Gate Charge V_{DS} = -80 V, I_D = -8.0 A, Q_{gs} Gate-Source Charge V_{GS} = -10 V Q_{gd} Gate-Drain Charge (Note 4) Orain-Source Diode Characteristics and Maximum Ratings s Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current		35	80	ns	
Q _{gs} Gate-Source Charge V _{GS} = -10 V Q _{gd} Gate-Drain Charge (Note 4) Orain-Source Diode Characteristics and Maximum Ratings s Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current		12	15	nC	
Drain-Source Diode Characteristics and Maximum Ratings (Note 4) S Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current		3.0		nC	
Drain-Source Diode Characteristics and Maximum Ratings s Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current		6.4		nC	
S Maximum Continuous Drain-Source Diode Forward Current SM Maximum Pulsed Drain-Source Diode Forward Current					
SM Maximum Pulsed Drain-Source Diode Forward Current	1		0.0	•	
			-8.0	A	
			-32	A	
$_{\rm rr}$ Reverse Recovery Time V _{GS} = 0 V, I _S = -8.0 A,		98	-4.0	ns	
$\frac{q_{\rm rr}}{q_{\rm rr}} = \frac{Reverse}{Recovery Charge} = \frac{v_{\rm GS} - 0.5 \text{A}}{dl_{\rm F}} / dt = 100 \text{A}/\mu\text{s}$		0.35		μC	
	I	0.00		μΟ	











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FQB8P10 ---

P-Channel QFET[®] MOSFET



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